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PATENT
ATTORNEY DOCKET NO.: 046124-5318

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Fumitsugu FUKUYO et al.

Application No.: 10/507,392

§ 371 Date : April 8, 2005

For: LASER PROCESSING METHOD

)
)
) Confirmation No.: 1798
)
) Group Art Unit: 2812
)
) Examiner: To be Assigned
)
)

U.S. Patent and Trademark Office
Customer Service Window
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), Applicants bring to the attention of the Examiner the documents listed on the attached PTO-1449. This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits for the above-referenced application.

The International Search Report from the Japanese Patent Office issued in the PCT application from which this National Phase U.S. Application derives is enclosed and cites JP-4-111800, JP 10-305420, U.S. Patent No. 5,211,805, the Midorikawa article, WO 02/22301, the Sano article, the Miura article and the Hayashi article. The International Preliminary Examination Report was previously submitted.

The relevance of the remaining non-English language documents can be understood from the figures respectively therein and the English language abstracts.

The referenced documents are listed on the PTO Form 1449. Applicants respectfully request that the Examiner consider the listed documents and evidence that consideration by making appropriate notations on the attached PTO Form-1449. Copies of the non-U.S. patent documents are enclosed.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If it should be determined that any of the listed documents do not constitute "prior art" under United States law, Applicants reserve the right to present to the Office the relevant facts and law regarding the appropriate status of such document.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

Except for issue fees payable under 37 C.F.R. § 1.18, the Commissioner is hereby authorized by this paper to charge any additional fees during the entire pendency of this application including fees due under 37 C.F.R. § 1.16 and 1.17 which may be required, including any required extension of time fees, or credit any overpayment to Deposit Account No. 50-0310.

This paragraph is intended to be a **CONSTRUCTIVE PETITION FOR EXTENSION OF TIME** in accordance with 37 C.F.R. § 1.136(a)(3).

Respectfully submitted,

MORGAN, LEWIS & BOCKIUS LLP

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Dated: May 4, 2005

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**INFORMATION DISCLOSURE**

(Use several sheets if necessary)

PTO Form-1449Attorney Docket No.:
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Fumitsugu FUKUYO et al.**PAGE 1**

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub Class	Filing Date
	4,562,333	12/31/1985	Taub et al.			
	5,211,805	05/18/1993	Rangaswamy			
	5,254,833	10/19/1993	Okiyama			
	5,543,365	08/06/1996	Wills et al.			
	5,622,540	04/22/1997	Stevens			
	5,637,244	06/10/1997	Erokhin			
	5,776,220	07/07/1998	Allaire et al.			
	5,826,772	10/27/1998	Ariglio et al.			
	6,055,829	05/02/2000	Witzmann et al.			
	6,211,488	04/03/2001	Hoekstra et al.			
	6,252,197	06/26/2001	Hoekstra et al.			
	6,257,224	07/10/2001	Yoshino et al.			
	6,259,058	07/10/2001	Hoekstra			
	6,322,958	11/27/2001	Hayashi			
	6,420,678	07/16/2002	Hoekstra			
	6,489,588	12/03/2002	Hoekstra et al.			
	2002/0006765	01/17/2002	Michel et al.			
	2003/0024909	02/06/2003	Hoekstra et al.			

Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

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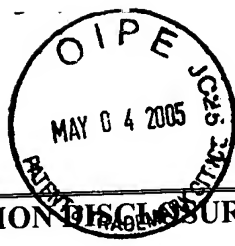
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation	
						Yes	No
	JP 4-111800 A	04/13/1992	Japan			X	
	JP 10-305420 A	11/17/1998	Japan			Abstract	
	WO 02/22301	03/21/2002	WIPO			Abstract	
	JP 07-040336	02/10/1995	Japan			Abstract	
	JP 10-163780	06/19/1998	Japan			Abstract	
	JP 11-138896	05/25/1999	Japan			Abstract	
	JP 11-221684	08/17/1999	Japan			Abstract	
	JP 11-267861	10/05/1999	Japan			Abstract	
	JP 2000-015467	01/18/2000	Japan			Abstract	
	JP 2000-219528	08/08/2000	Japan			Abstract	
	JP 11-163403	06/18/1999	Japan			X	
	JP 11-177137	07/02/1999	Japan			X	
	JP 46-24989	07/19/1971	Japan				X

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	§ 371 Date: April 8, 2005	Group: 2812

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
	Katsuyoshi MIDORIKAWA, "Femto-byo Laser ni Genjo to Kako Oyo", Dai 45 Kai Laser Netsukako Kenkyukai Ronbunshu, December 1998
	Tomokazu SANO et al., "Pico-byo Pulse Laser ni yoru Silicon no Kako Tokusei Hyoka - Tan-Pulse Tanhacho Laser ni yoru Denshi Zairyo no Seimitsu Bisai Kako (Dai 1 ho)-" Japan Welding Society Zenkoku Taikai Koen Gaiyo March 13, 2000 (13.03.00), 66th series, pages 72 TO 73
	Kiyotaka MIURA, Kazuyuki HIRAO, "Femto-byo Laser Shosha ni yoru Glass Naibu eno Hikari Yuki Kozo Keisei", Dai 42 Kai Laser Netsukako Kenkyukai Ronbunshu, November 1997, ISBN: 4-947684-15-1, page 104, line 4 to page 109, lien 5
	Ken'ichi HAYASHI, "Kotai Laser Kochoha ni yoru Glass Kiban no Naibu Marking", Dai 45 Kai Laser Netsukako Kenkyukai Ronbunshu, October, 1998, ISBN: 4-947684-321-6
	T. Yajima et al., New Version Laser Handbook, published by Asakusa Shoten, June 15, 1989, pps. 666-669
	Tooling Machine Series, Laser Machining, published by Taiga Shuppan, Inc., September 10, 1990, pps. 91-96
	Electronic Material. No. 9 on 2002, published by Kogyo Chousakai, pps. 17-21 (with full English translation)
	F. Fukuyo et al., "Stealth Dicing Technology for Ultra Thin Wafer", presented at 2003 ICEP (International Conference on Electronics Packaging), April 16-18, 2003, Tokyo, Japan
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